

Description

The VSM75N20 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in automotive applications and a wide variety of other applications.

General Features

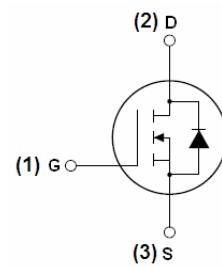
- $V_{DSS} = 200V, I_D = 75A$
- $R_{DS(ON)} < 20m\Omega @ V_{GS}=10V$
- Good stability and uniformity with high E_{AS}
- Special process technology for high ESD capability
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

Application

- Automotive applications
- Hard switched and high frequency circuits
- Uninterruptible power supply



TO-247



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM75N20-T7	VSM75N20	TO-247	-	-	-

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	200	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	75	A
Drain Current-Continuous($T_c=100^\circ C$)	$I_D (100^\circ C)$	53	A
Pulsed Drain Current	I_{DM}	300	A
Maximum Power Dissipation	P_D	360	W
Derating factor		2.4	W/ $^\circ C$
Single pulse avalanche energy (Note 3)	E_{AS}	2200	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 1)	$R_{\theta JC}$	0.42	°C/W
--	-----------------	------	------

Electrical Characteristics ($T_c=25^\circ C$ unless otherwise noted)

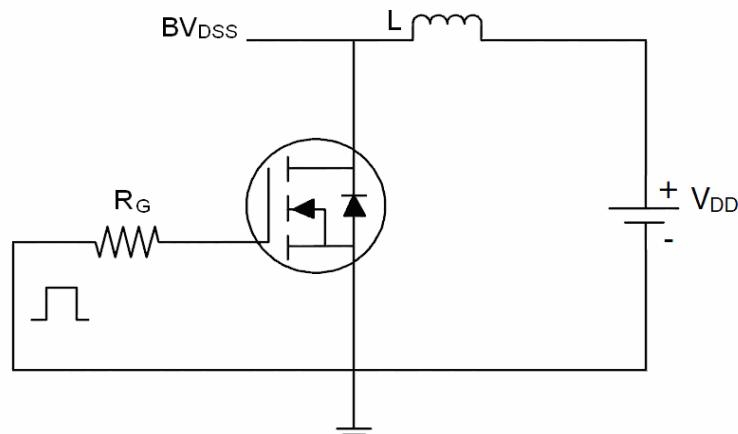
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	200	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=200V, V_{GS}=0V$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 200	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.5	3.5	4.5	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=40A$	-	17.8	20	$m\Omega$
Forward Transconductance	g_{FS}	$V_{DS}=50V, I_D=40A$		79	-	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{DS}=50V, V_{GS}=0V, F=1.0MHz$	-	6990	-	PF
Output Capacitance	C_{oss}		-	950	-	PF
Reverse Transfer Capacitance	C_{rss}		-	700	-	PF
Switching Characteristics						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=100V, I_D=40A, V_{GS}=10V, R_G=2.7\Omega$	-	17	-	nS
Turn-on Rise Time	t_r		-	18	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	56	-	nS
Turn-Off Fall Time	t_f		-	22	-	nS
Total Gate Charge	Q_g	ID=40A, VDD=100V, VGS=10V	-	140	-	nC
Gate-Source Charge	Q_{gs}		-	40	-	nC
Gate-Drain Charge	Q_{gd}		-	45	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S=75A$	-	-	1.2	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ C, IF = 40A$ $di/dt = 100A/\mu s$ ^(Note 2)	-	136	-	nS
Reverse Recovery Charge	Q_{rr}		-	458	-	nC

Notes:

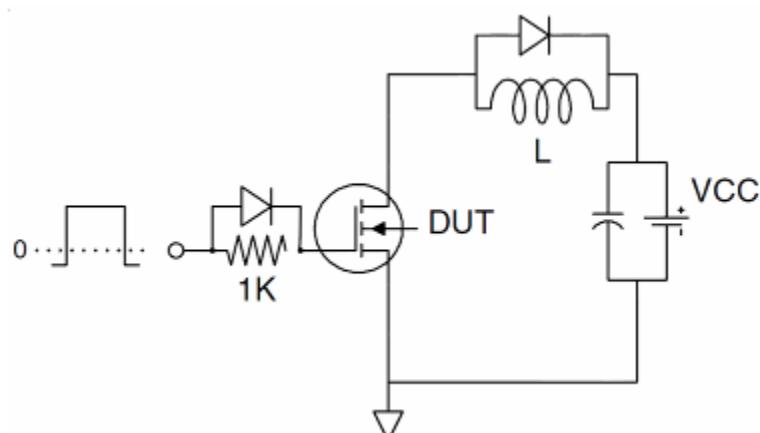
1. Surface Mounted on FR4 Board, $t \leq 10$ sec.
2. Pulse Test: Pulse Width $\leq 400\mu s$, Duty Cycle $\leq 2\%$.
3. EAS condition: $T_J=25^\circ C, V_{DD}=50V, V_G=10V, L=1mH, R_g=25\Omega, I_{AS}=66A$
4. $I_{SD} \leq 125A, di/dt \leq 260A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175^\circ C$

Test Circuit

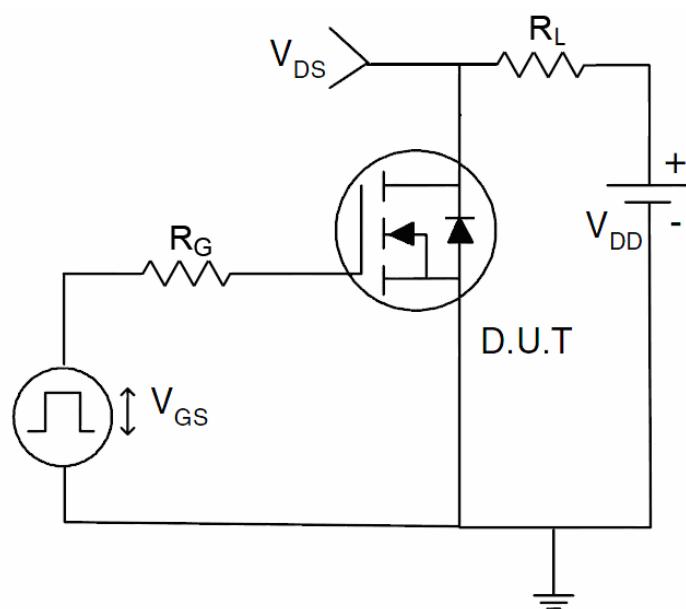
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics

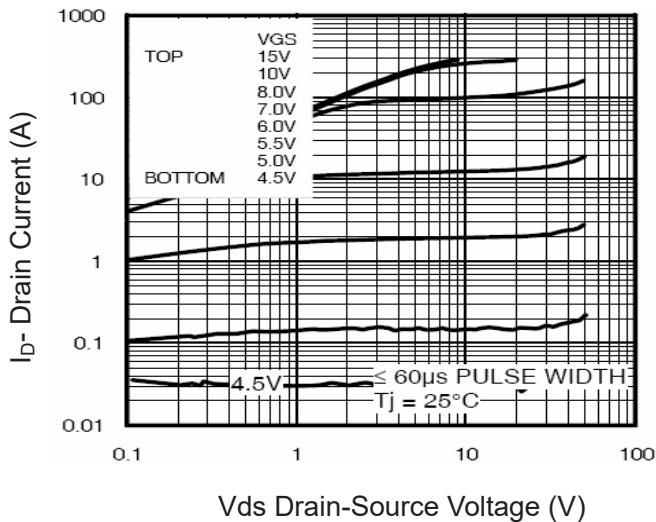


Figure 1 Output Characteristics

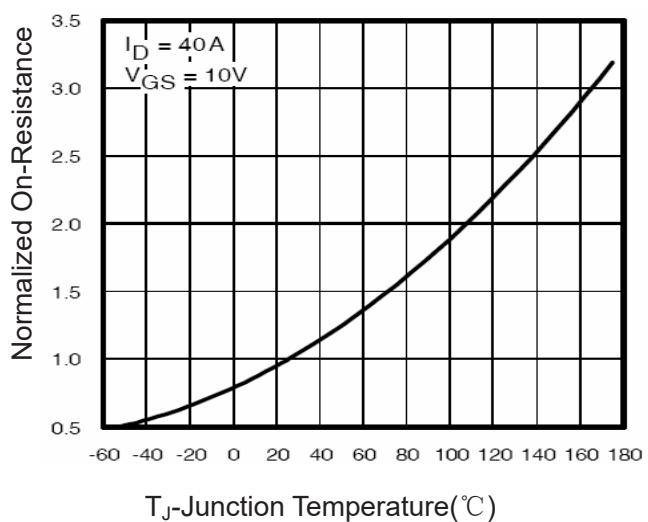


Figure 4 Rdson-JunctionTemperature

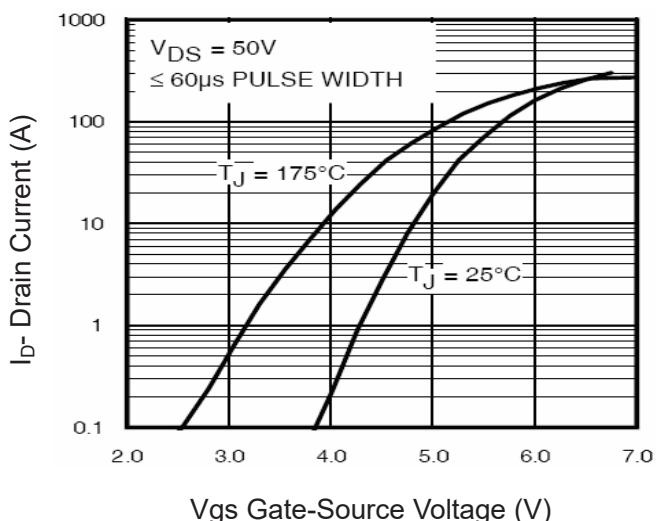


Figure 2 Transfer Characteristics

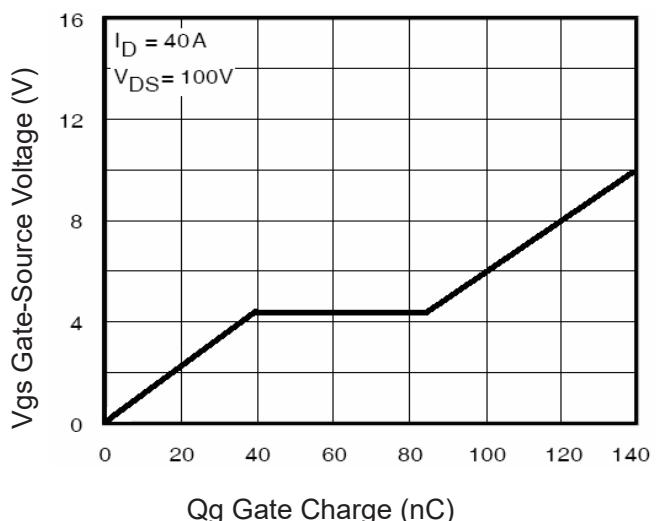


Figure 5 Gate Charge

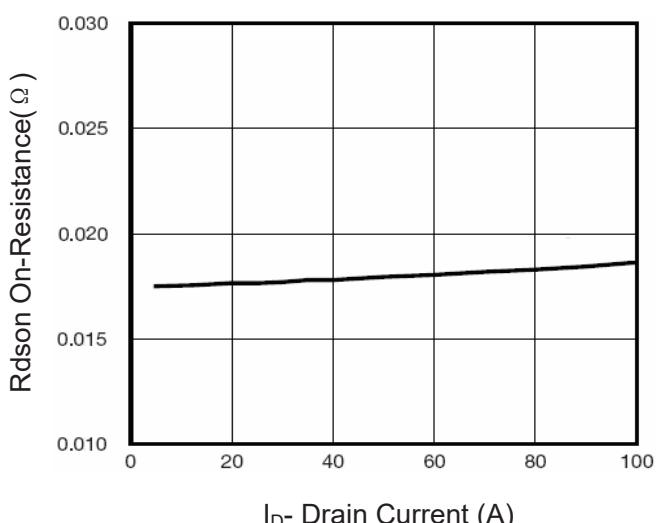


Figure 3 Rdson- Drain Current

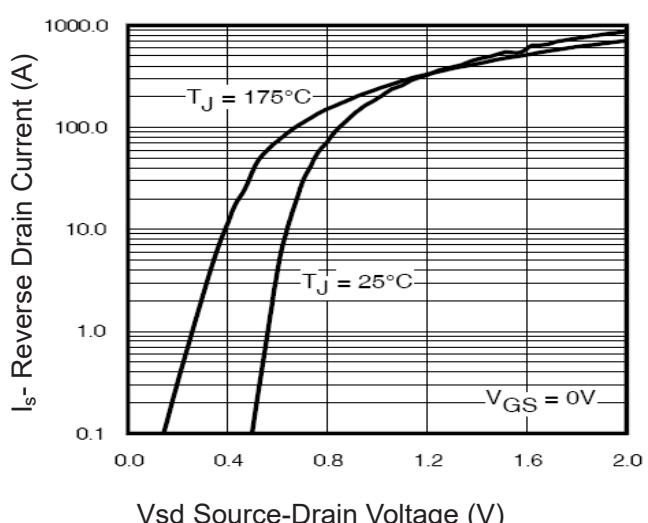


Figure 6 Source- Drain Diode Forward

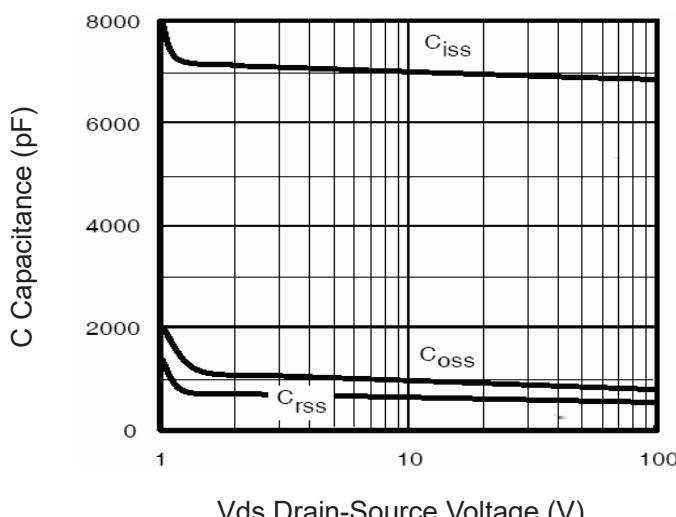


Figure 7 Capacitance vs Vds

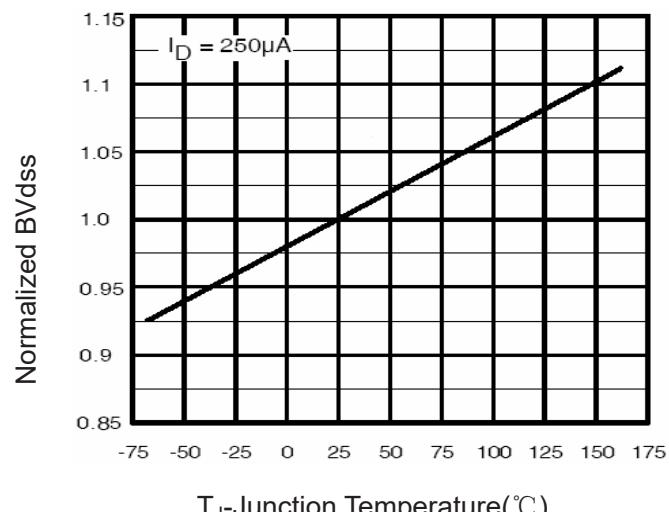


Figure 9 BV_{DSS} vs Junction Temperature

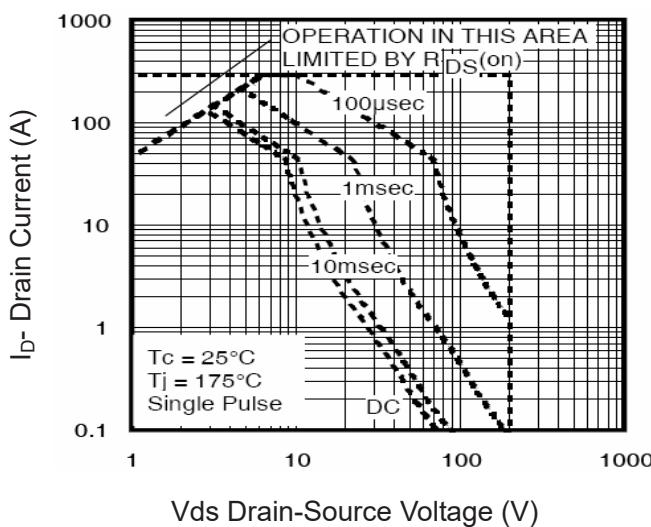


Figure 8 Safe Operation Area

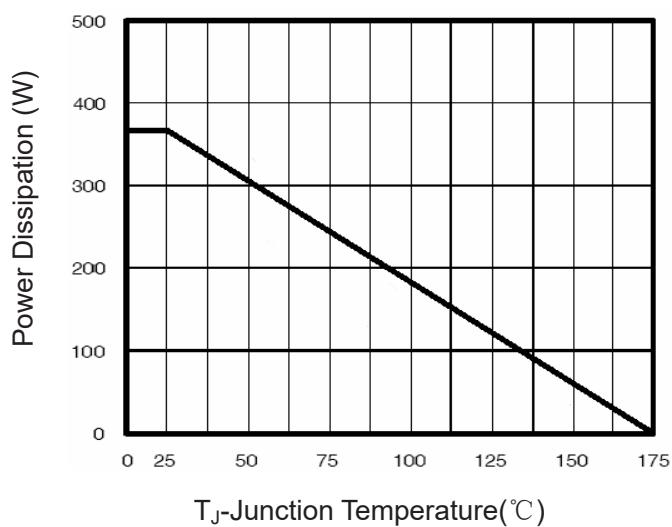


Figure 10 Power De-rating

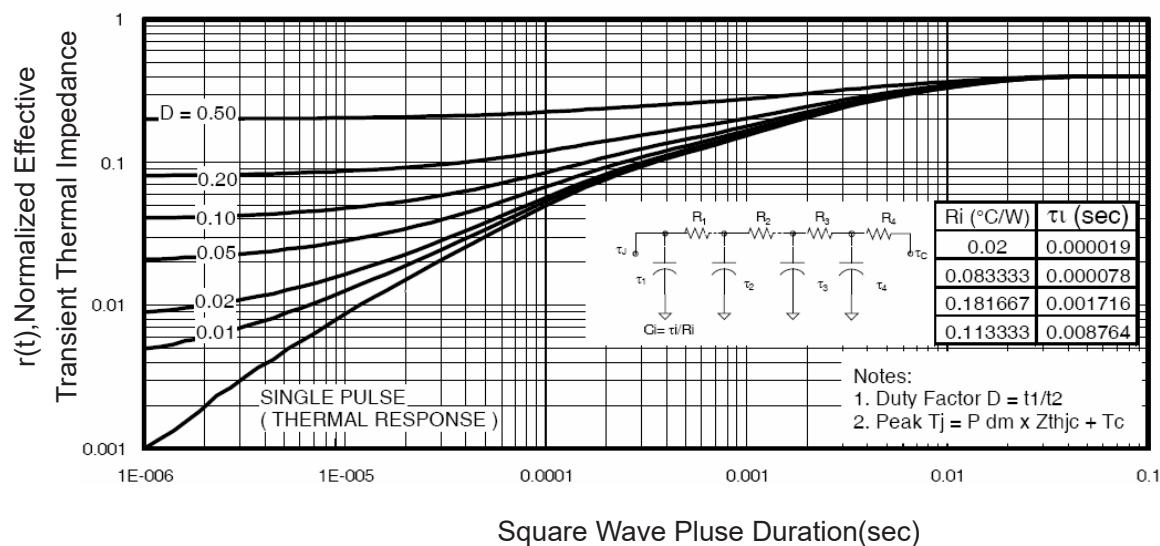


Figure 11 Normalized Maximum Transient Thermal Impedance